Title: The influence of structural disorder and phonon on the metal-to-insulator transition of VO_2

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We used temperature-dependent XAFS measurements to examine the local structural properties around vanadium atoms at the V K edge from VO₂ films. A direct comparison of the simultaneously-measured resistance and XAFS regarding the VO₂ films showed that the thermally-driven structural transition occurred prior to the resistance transition during a heating, while this change simultaneously occurred during a cooling. EXAFS measurements revealed significant increases of the Debye-Waller factors of the V-O and V-V pairs in the {111} direction of the R-phase VO₂ that are due to the phonons of the V-V arrays along the same direction in a metallic phase. FEFF calculations showed nearly no changes in local density of states in the V 3d orbitals. The thermally-induced phonons in the {111} direction assist the delocalization of the V $3d^1$ electrons in the R phase VO₂ and the electrons likely migrate via the V-V array in the {111} direction as well as the V-V dimerization along the c-axis. This study clarifies that a tetragonal symmetry is essentially important for the metallic phase in VO₂. The existence of a substantial amount of structural disorder on the V-V pairs along the c-axis in both the M1 and R phases indicates the structural instability of the V-V arrays in the axis. The anomalous structural disorder that was observed on all of the atomic sites at the structural phase transition prevented the migration of the V $3d^1$ electrons, resulting in a Mott insulator in the M₂-phase VO₂.

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